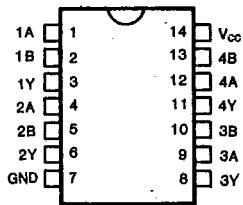


**KS54HCTLs 32
KS74HCTLs 32****Quad 2-Input OR Gates****FEATURES**

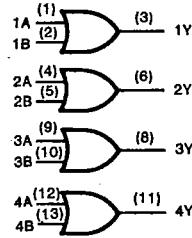
- Function, pin-out, speed and drive compatibility with 54/74LS logic family
- Low power consumption characteristic of CMOS
- High-Drive-Current outputs:
 $I_{OL} = 8 \text{ mA} @ V_{OL} = 0.5V$
- Inputs and outputs interface directly with TTL, NMOS and CMOS devices
- Wide operating voltage range: 4.5V to 5.5V
- Characterized for operation over industrial and military temperature ranges:
KS74HCTLs: -40°C to $+85^{\circ}\text{C}$
KS54HCTLs: -55°C to $+125^{\circ}\text{C}$
- Package options include plastic "small outline" packages, standard plastic and ceramic 300-mil DIPs

PIN CONFIGURATION**DESCRIPTION**

These devices contain four independent 2-input OR gates. They perform the Boolean functions $Y = A + B$ or $Y = \overline{A} \cdot \overline{B}$.

These devices provide speeds and drive capability equivalent to their ALSTTL counterparts and yet maintain CMOS power levels. The input and output voltage levels allow direct interface with TTL, NMOS and CMOS devices without any external components.

All inputs and outputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

LOGIC DIAGRAM**FUNCTION TABLE**

(Each Gate)

| Inputs | | Output |
|--------|---|--------|
| A | B | Y |
| H | X | H |
| X | H | H |
| L | L | L |



SAMSUNG SEMICONDUCTOR

**KS54HCTL32
KS74HCTL32****Quad 2-Input OR Gates**

T-43-21

Absolute Maximum Ratings*

| | |
|---|-----------------|
| Supply Voltage Range V_{CC} , | -0.5V to +7V |
| DC Input Diode Current, I_{IK} ($V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$) | ± 20 mA |
| DC Output Diode Current, I_{OK} ($V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$) | ± 20 mA |
| Continuous Output Current Per Pin, I_O ($-0.5V < V_O < V_{CC} + 0.5V$) | ± 35 mA |
| Continuous Current Through V_{CC} or GND pins | ± 125 mA |
| Storage Temperature Range, T_{STG} | -65°C to +150°C |
| Power Dissipation Per Package, P_d^{\dagger} | 500 mW |

* Absolute Maximum Ratings are those values beyond which permanent damage to the device may occur. These are stress ratings only and functional operation of the device at or beyond them is not implied. Long exposure to these conditions may affect device reliability.

† Power Dissipation temperature derating:
Plastic Package (N): -12mW/°C from 65°C to 85°C
Ceramic Package (J): -12mW/°C from 100°C to 125°C

Recommended Operating Conditions

| | |
|--|---|
| Supply Voltage, V_{CC} | 4.5V to 5.5V |
| DC Input & Output Voltages*, V_{IN}, V_{OUT} | 0V to V_{CC} |
| Operating Temperature Range | KS74HCTL32: -40°C to +85°C KS54HCTL32: -55°C to +125°C |
| Input Rise & Fall Times, t_r, t_f | Max 500 ns |
| * Unused inputs must always be tied to an appropriate logic voltage level (either V_{CC} or GND) | |

DC ELECTRICAL CHARACTERISTICS ($V_{CC}=5V \pm 10\%$ Unless Otherwise Specified)

| Characteristic | Symbol | Test Conditions | $T_a = 25^\circ C$ | | KS74HCTL32 | KS54HCTL32 | Unit |
|--------------------------------------|-----------------|--|--------------------|----------------------|----------------------|---------------------|---------|
| | | | Typ | Guaranteed Limits | | | |
| Minimum High-Level Input Voltage | V_{IH} | | 2.0 | 2.0 | 2.0 | 2.0 | V |
| Maximum Low-Level Input Voltage | V_{IL} | | 0.8 | 0.8 | 0.8 | 0.8 | V |
| Minimum High-Level Output Voltage | V_{OH} | $V_{IN}=V_{IH}$ or V_{IL} $I_O=-20\mu A$ $I_O=-4mA$ | V_{CC} 4.2 | $V_{CC}-0.1$ 3.98 | $V_{CC}-0.1$ 3.84 | $V_{CC}-0.1$ 3.7 | V |
| Maximum Low-Level Output Voltage | V_{OL} | $V_{IN}=V_{IH}$ or V_{IL} $I_O=20\mu A$ $I_O=4mA$ $I_O=8mA$ | 0 | 0.1 0.26 0.39 | 0.1 0.33 0.5 | 0.1 0.4 | V |
| Maximum Input Current | I_{IN} | $V_{IN}=V_{CC}$ or GND | | ± 0.1 | ± 1.0 | ± 1.0 | μA |
| Maximum Quiescent Supply Current | I_{CC} | $V_{IN}=V_{CC}$ or GND $I_{OUT}=0\mu A$ | | 2.0 | 20.0 | 40.0 | μA |
| Additional Worst Case Supply Current | ΔI_{CC} | per input pin $V_I=2.4V$ other Inputs: at V_{CC} or GND $I_{OUT}=0\mu A$ | | 2.7 | 2.9 | 3.0 | mA |

AC ELECTRICAL CHARACTERISTICS (Input $t_r, t_f \leq 6$ ns), HCTL32

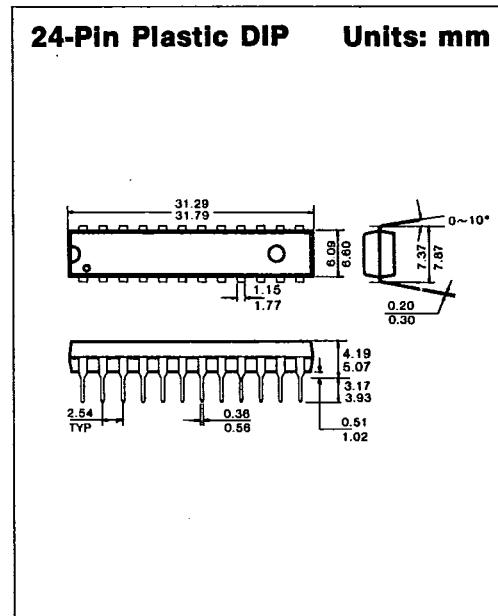
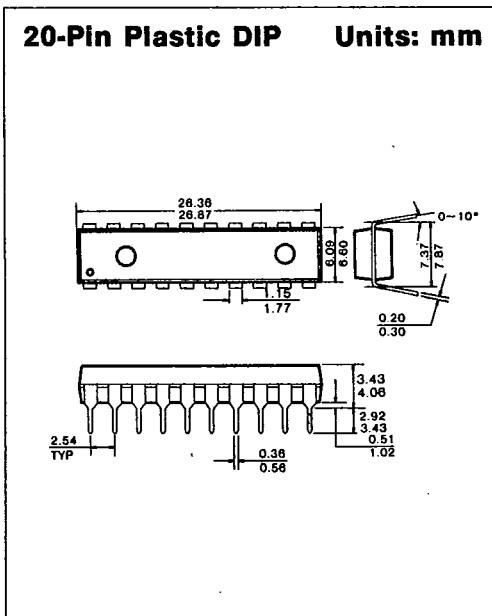
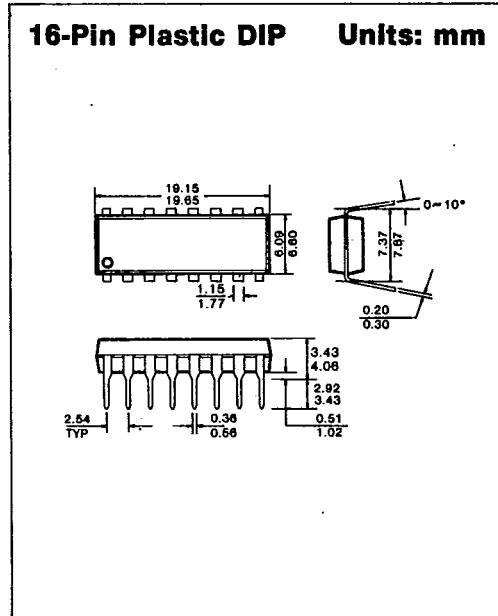
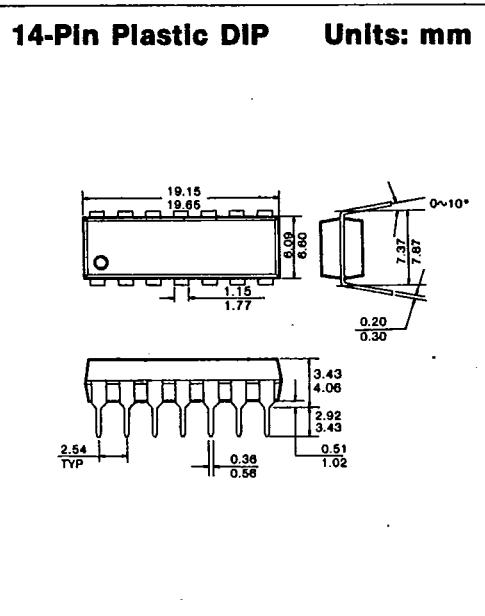
| Characteristic | Symbol | Conditions [†] | $T_a = 25^\circ C$ | | KS74HCTL32 | KS54 HCTL32 | Unit |
|--------------------------------|-----------|-------------------------|--------------------|-------------------|------------|-------------|------|
| | | | Typ | Guaranteed Limits | | | |
| Maximum Propagation Delay | t_{PLH} | $C_L=50pF$ | 13 | 17 | 22 | 26 | ns |
| | t_{PHL} | | 13 | 17 | 22 | 26 | |
| Maximum Input Capacitance | C_{IN} | | 5 | | | | pF |
| Power Dissipation Capacitance* | C_{PD} | (per gate) | 15 | | | | pF |

* C_{PD} determines the no-load dynamic power dissipation: $P_D=C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$.

† For AC switching test circuits and timing waveforms see section 2.



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PACKAGE DIMENSIONS**T-90-20****1. PLASTIC PACKAGES**

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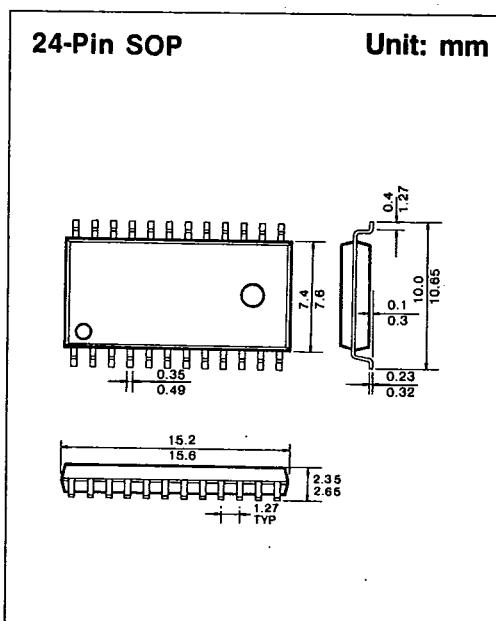
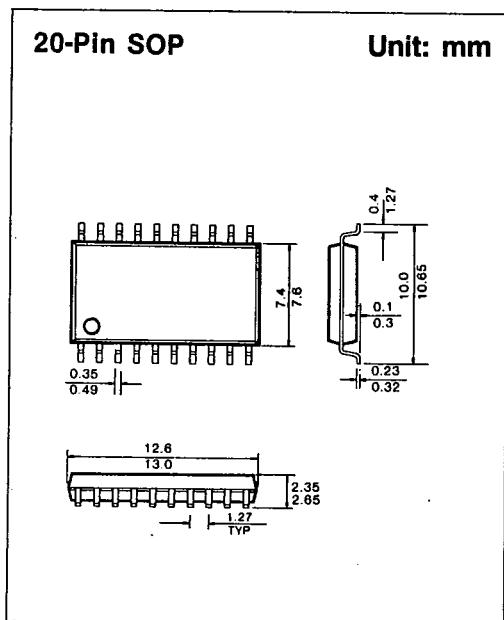
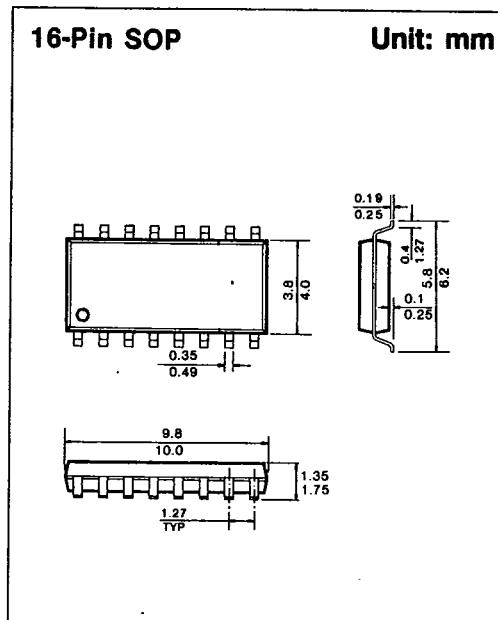
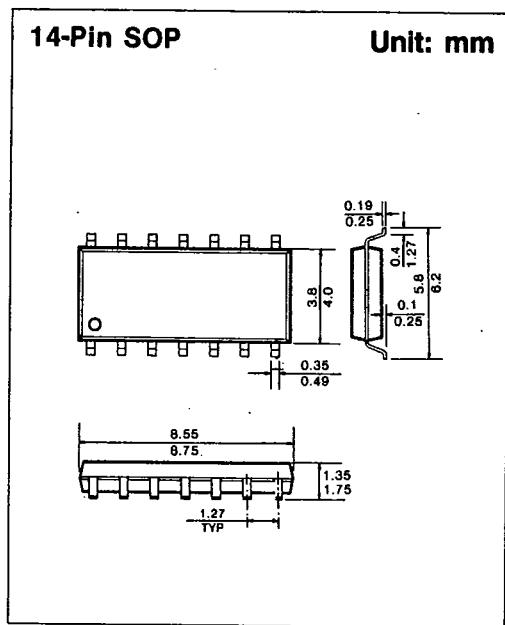


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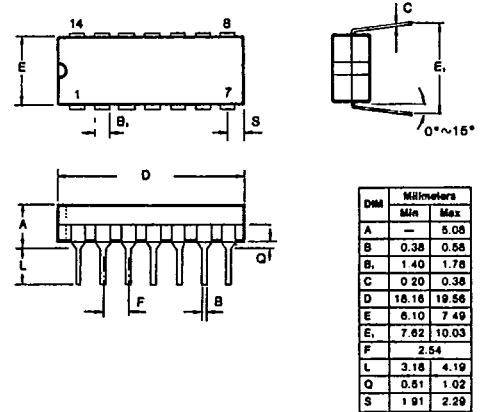
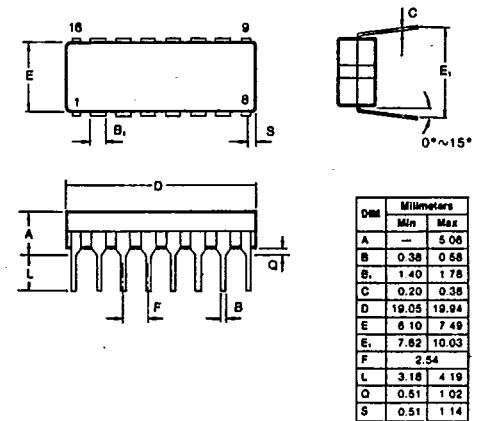
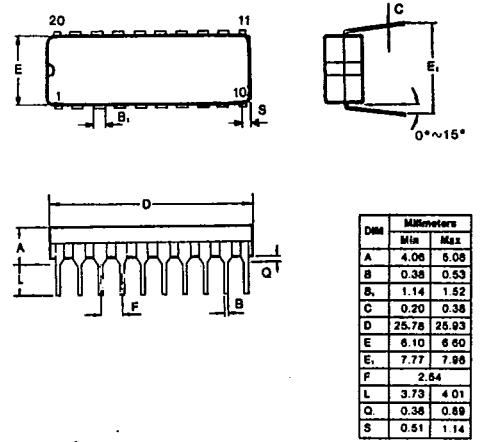
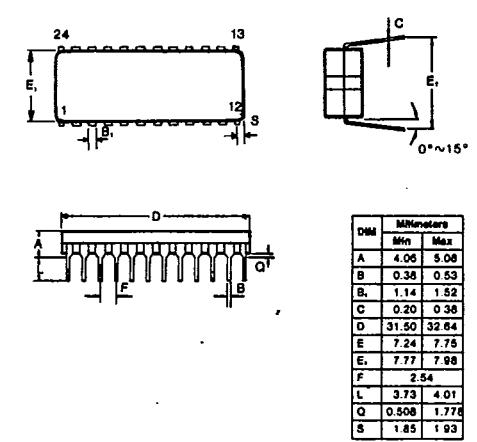
PACKAGE DIMENSIONS*T-90-20*

SAMSUNG SEMICONDUCTOR

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PACKAGE DIMENSIONST-90-20**2. CERAMIC PACKAGES****14-Pin Ceramic DIP Units: mm****16-Pin Ceramic DIP Units: mm****20-Pin Ceramic DIP Units: mm****24-Pin Ceramic DIP Units: mm**

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